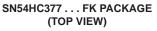
- **Eight Flip-Flops With Single-Rail Outputs**
- **Clock Enable Latched to Avoid False** Clocking
- **Applications Include:**
 - Buffer/Storage Registers
 - Shift Registers
 - Pattern Generators
- **Package Options Include Plastic** Small-Outline (DW) and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

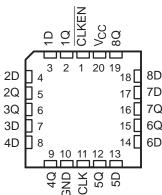
description

These devices are positive-edge-triggered octal D-type flip-flops with an enable input. The 'HC377 are similar to the 'HC273 but feature a latched clock-enable (CLKEN) input instead of a common clear.

Information at the data (D) inputs meeting the setup time requirements is transferred to the Q outputs on the positive-going edge of the clock (CLK) pulse if CLKEN is low. Clock triggering occurs at a particular voltage level and is not directly related to the transition time of the positive-going pulse. When CLK is at either the high or low level, the D input has no effect at the output. These devices are designed to prevent false clocking by transitions at CLKEN.

SN54HC377 SN74HC377		OR	
CLKEN		20] V _{CC}
1Q [2	19] 8Q
1D [3	18] 8D
2D [4	17] 7D
2Q [5	16] 7Q
3Q [6	15] 6Q
3D [7	14] 6D
4D [8	13] 5D
4Q [9	12] 5Q
GND [10	11] CLK





The SN54HC377 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74HC377 is characterized for operation from -40°C to 85°C.

	FUNCTION TABLE (each flip-flop)									
	NPUTS		OUTPUT							
CLKEN	CLK	D	Q							
н	Х	Х	Q ₀							
L	\uparrow	Н	н							
L	\uparrow	L	L							
Х	L	Х	Q ₀							



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

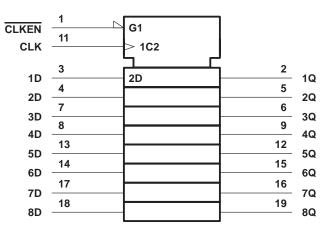
PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



SN54HC377, SN74HC377 OCTAL D-TYPE FLIP-FLOPS WITH CLOCK ENABLE

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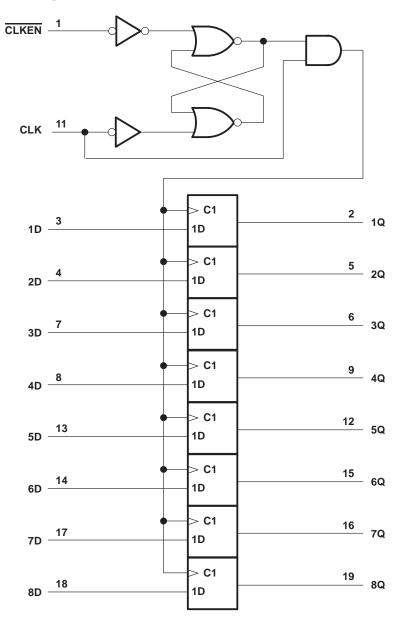
logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



logic diagram (positive logic)





absolute maximum ratings over operating free-air temperature range[†]

	nA nA nA nA /W
N package	/W
Storage temperature range, T _{stg}	°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

recommended operating conditions

			SN	154HC37	7	SN74HC377			
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage		2	5	6	2	5	6	V
		$V_{CC} = 2 V$	1.5			1.5			
VIH	High-level input voltage	$V_{CC} = 4.5 V$	3.15			3.15			V
		VCC = 6 V	4.2			4.2			
VIL	Low-level input voltage	$V_{CC} = 2 V$	0		0.5	0		0.5	
		$V_{CC} = 4.5 V$	0		1.35	0		1.35	V
		ACC = 6 A	0		1.8	0		1.8	
VI	Input voltage		0		VCC	0		VCC	V
VO	Output voltage		0		VCC	0		VCC	V
		$V_{CC} = 2 V$	0		1000	0		1000	
tt	Input transition (rise and fall) time	$V_{CC} = 4.5 V$	0		500	0		500	ns
		VCC = 6 V	0		400	0		400	
ТА	Operating free-air temperature		-55		125	-40		85	°C



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CO	NDITIONS	Vee	Т	A = 25°C	;	SN54HC377		SN74HC377		UNIT
PARAMETER	TEST CC	INDITIONS	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
			2 V	1.9	1.998		1.9		1.9		
		I _{OH} = -20 μA	4.5 V	4.4	4.499		4.4		4.4		
VOH	H VI = VIH or VIL		6 V	5.9	5.999		5.9		5.9		V
		I _{OH} = -4 mA	4.5 V	3.98	4.3		3.7		3.84		
		I _{OH} = -5.2 mA	6 V	5.48	5.8		5.2		5.34		
			2 V		0.002	0.1		0.1		0.1	
		I _{OL} = 20 μA	4.5 V		0.001	0.1		0.1		0.1	
VOL	$V_I = V_{IH} \text{ or } V_{IL}$		6 V		0.001	0.1		0.1		0.1	V
		$I_{OL} = 4 \text{ mA}$	4.5 V		0.17	0.26		0.4		0.33	
		I _{OL} = 5.2 mA	6 V		0.15	0.26		0.4		0.33	
l	$V_I = V_{CC} \text{ or } 0$		6 V		±0.1	±100		±1000		±1000	nA
ICC	$V_{I} = V_{CC} \text{ or } 0,$	I _O = 0	6 V			8		160		80	μΑ
Ci			2 V to 6 V		3	10		10		10	pF

timing requirements over recommended operating free-air temperature range (unless otherwise noted)

			N.	T _A = 1	25°C	SN54H	IC377	SN74H	IC377	UNIT	
			Vcc	MIN	MAX	MIN	MAX	MIN	MAX	UNIT	
			2	2 V	0	5	0	3	0	4	
fclock	Clock frequency		4.5 V	0	25	0	16	0	20	MHz	
			6 V	0	29	0	19	0	23		
		2 V	100		150		125				
tw	tw Pulse duration, CLK high or low		4.5 V	20		30		25		ns	
			6 V	17		25		21			
		D	2 V	100		150		125		ns	
			4.5 V	20		30		25			
	Satur time before CLK^{\uparrow}		6 V	17		25		21			
t _{su}	Setup time before CLK		2 V	100		150		125			
		CLKEN high or low	4.5 V	20		30		25			
		6 V	17		25		21				
			2 V	5		5		5			
th	Hold time after CLK↑	CLKEN inactive or active, data	4.5 V	5		5		5		ns	
	Pulse duration, CLK high or I Setup time before CLK1		6 V	5		5		5			



SN54HC377, SN74HC377 **OCTAL D-TYPE FLIP-FLOPS** WITH CLOCK ENABLE

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switching characteristics over recommended operating free-air temperature range, $C_L = 50 \text{ pF}$ (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	FROM TO Voo		T,	₄ = 25°C	;	SN54H	IC377	SN74H	IC377	UNIT
PARAMETER	(INPUT)	(OUTPUT)	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
			2 V	5	11		3		4		
f _{max}			4.5 V	25	54		16		20		MHz
			6 V	29	64		19		23		
			2 V		56	160		240		200	
^t pd	CLK	Any	4.5 V		15	32		48		40	ns
			6 V		12	27		41		34	
			2 V		38	75		110		95	
tt		Any	4.5 V		8	15		22		19	ns
			6 V		6	13		19		16	

operating characteristics, $T_A = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd}	Power dissipation capacitance per flip-flop	No load	30	pF



Vcc **High-Level** 50% 50% Pulse **From Output** Test 0 V **Under Test** Point $C_L = 50 \text{ pF}$ Vcc (see Note A) Low-Level 50% 50% Pulse 0 V LOAD CIRCUIT VOLTAGE WAVEFORMS PULSE DURATIONS Vcc Input 50% 50% 0 V tргн ^tPHL - Vcc VOH In-Phase Reference 90% 90% 50% 50% -_<u>10%</u> V_{OL} 50% Output Input 0 V - tf t_{su} th 🗲 tPHL ^tPLH - Vcc VOH Data 90% 90% 90% 90% **Out-of-Phase** 50% 50% 50% ⊾10% 50% Input <u>10%</u> 0 V Output Vol — tf - t_r – tr tr **VOLTAGE WAVEFORMS VOLTAGE WAVEFORMS** SETUP AND HOLD AND INPUT RISE AND FALL TIMES PROPAGATION DELAY AND OUTPUT TRANSITION TIMES

PARAMETER MEASUREMENT INFORMATION

NOTES: A. CL includes probe and test-fixture capacitance.

- B. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, Z_O = 50 Ω , t_r = 6 ns, t_f = 6 ns.
- C. For clock inputs, f_{max} is measured when the input duty cycle is 50%.
- D. The outputs are measured one at a time with one input transition per measurement.
- E. tPLH and tPHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



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